

<b>Notice of References Cited</b>	Application/Control No. 10/058,305	Applicant(s)/Patent Under Reexamination NAKASAKA ET AL.	
	Examiner Hai H. Huynh	Art Unit 3747	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,148,791 A	11-2000	Fujieda et al.	123/295
*	B	US-6,286,478 B1	09-2001	Atago et al.	123/306
*	C	US-6,343,585 B1	02-2002	Fujieda et al.	123/295
*	D	US-6,453,871 B1	09-2002	Fujieda et al.	123/295
*	E	US-6,564,763 B2	05-2003	Shiraishi et al.	123/90.15
*	F	US-2001/0045194	11-2001	Shiraishi et al.	123/90.15
*	G	US-2004/0231624 A1	11-2004	Shindou et al.	123/090.15
*	H	US-2002/0017256	02-2002	Shiraishi et al.	123/90.15
*	I	US-2005/0217620 A1	10-2005	Shindou, Shigeki	123/090.15
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004-132314	04-2004	Japan	Kato	F02D-41/04
	O	EP 1229230	08-2002		Nakasaka et al	F02D-33/02
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.